# Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | TOUCHAIS ET AL. | Examiner | Art Unit | Page 1 of 6

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Examiner

Jason M. Perilla

Applicant(s)/Patent Under
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TOUCHAIS ET AL.

Art Unit
Page 2 of 6

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Application/Control No. 10/533,861	Applicant(s)/Patent Under Reexamination TOUCHAIS ET AL.		
Examiner	Art Unit		
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